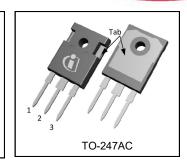
### IRFP140NPbF



V <sub>(BR)DSS</sub>	100V
R <sub>DS(on)</sub> max.	0.052Ω
I <sub>D</sub>	33A

# Gate Pin 1 Source Pin 3



G	D	s
Gate	Drain	Source

#### **Features**

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

#### **Description**

Fifth Generation HEXFET Power MOSFETs utilizes advanced processing techniques to achieve extremely low onresistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of other applications.

The TO-247AC package is preferred for commercial-industrial applications where higher power levels preclude th use of TO-220 devices. The TO-247AC is similar but superior to the earlier TO-218 package because of its isolated mounting hole.

Page part number	Race part number   Package Type		Standard Pack		
Base part number	Package Type	Form	Quantity	Orderable Part Number	
IRFP140NPbF	TO-247AC	Tube	25	IRFP140NPbF	

Symbol	Symbol Parameter		Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V S	33		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ©	23	Α	
I <sub>DM</sub>	Pulsed Drain Current ①⑤	110		
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	140	W	
	Linear Derating Factor	0.91	W/°C	
$V_{GS}$	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>			mJ	
Avalanche Current ①		16	А	
E <sub>AR</sub> Repetitive Avalanche Energy ①		14	mJ	
dv/dt	Peak Diode Recovery dv/dt③⑤	5.0	V/ns	
T <sub>J</sub>	Operating Junction and	-55 to + 175		
T <sub>STG</sub>	Storage Temperature Range			
	Soldering Temperature, for 10 seconds (1.6mm from case)	300		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)		

#### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case		1.1	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.24		°C/W
$R_{\theta JA}$	Junction-to-Ambient		40	



#### Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter		Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA <sup>⑤</sup>
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.052	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 16A ④
$V_{GS(th)}$	Gate Threshold Voltage			4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Trans conductance	11			S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 16A <sup>⑤</sup>
I	Drain-to-Source Leakage Current			25		$V_{DS} = 100V, V_{GS} = 0V$
IDSS	Dialii-to-Source Leakage Current			250	μΛ	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
ı	Gate-to-Source Forward Leakage			100	۰,۸	$V_{GS} = 20V$
IGSS	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V

#### Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

$Q_g$	Total Gate Charge	 	94		I <sub>D</sub> = 16A
$Q_{gs}$	Gate-to-Source Charge	 	15	nC	$V_{DS} = 80V$
$Q_{gd}$	Gate-to-Drain Charge	 	43		V <sub>GS</sub> = 10V, See Fig.6 and 13 ⊕⑤
$t_{d(on)}$	Turn-On Delay Time	 8.2			$V_{DD} = 50V$
t <sub>r</sub>	Rise Time	 39		20	I <sub>D</sub> = 16A
$t_{d(off)}$	Turn-Off Delay Time	 44		ns	$R_G = 5.1\Omega$
t <sub>f</sub>	Fall Time	 33			R <sub>D</sub> = 3.0Ω, See Fig.10④⑤
L <sub>D</sub>	Internal Drain Inductance	 5.0			Between lead, 6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance	 13		nH	from package and center of die contact
C <sub>iss</sub>	Input Capacitance	 1400			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance	 330		pF	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance	 170			f = 1.0MHz, See Fig.5®

#### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			33		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			110		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 16A, V_{GS} = 0V $ ④
t <sub>rr</sub>	Reverse Recovery Time		170	250	ns	$T_J = 25^{\circ}C$ , $I_F = 16A$
$Q_{rr}$	Reverse Recovery Charge		1.1	1.6	μC	di/dt = 100A/µs ⊕⑤

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ②  $V_{DD}$  = 25V,  $T_J$  = 25°C, L = 2.0mH,  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = 16A.(See fig. 12). ③  $I_{SD} \le$  16A, di/dt  $\le$  210A/ $\mu$ s,  $V_{DD} \le V_{(BR)DSS}$ ,  $T_J \le$  175°C.
- 4 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤ Uses IRF540N data and test conditions



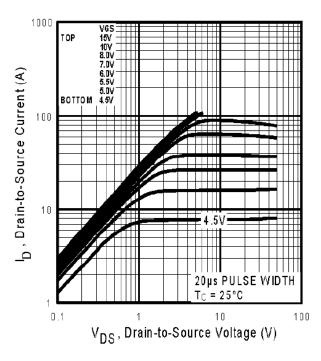


Fig. 1 Typical Output Characteristics

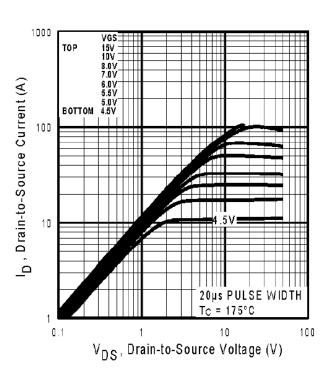


Fig. 2 Typical Output Characteristics

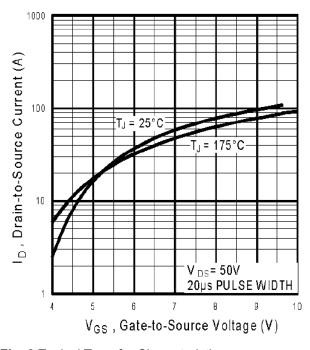


Fig. 3 Typical Transfer Characteristics

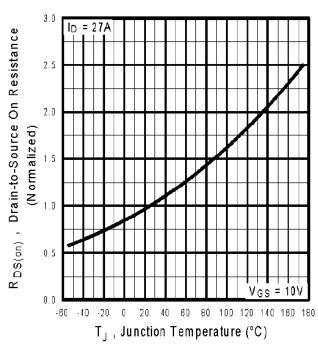
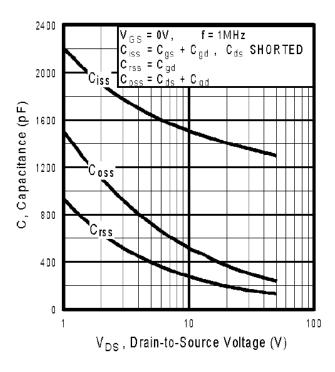
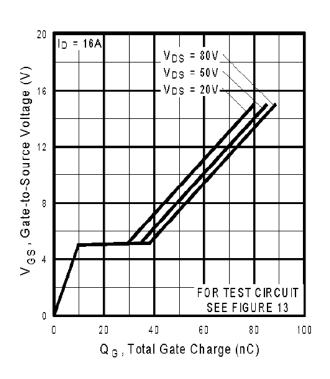


Fig. 4 Normalized On-Resistance vs. Temperature





**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

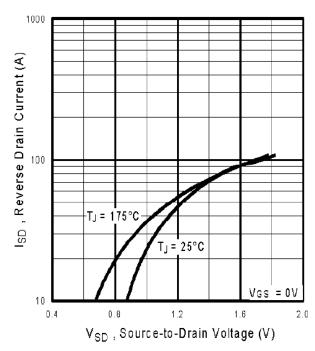


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

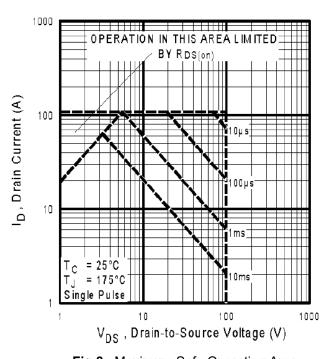
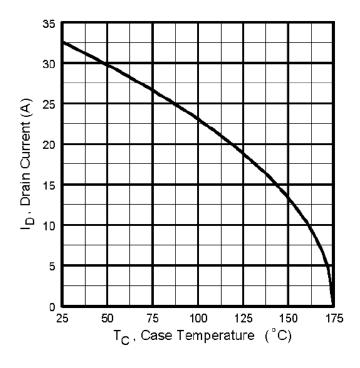


Fig 8. Maximum Safe Operating Area





**Fig 9.** Maximum Drain Current vs. Case Temperature

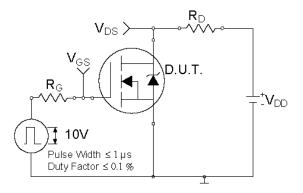


Fig 10a. Switching Time Test Circuit

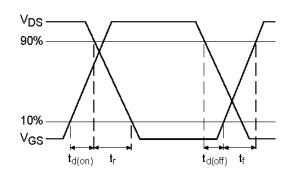


Fig 10a. Switching Time Waveforms

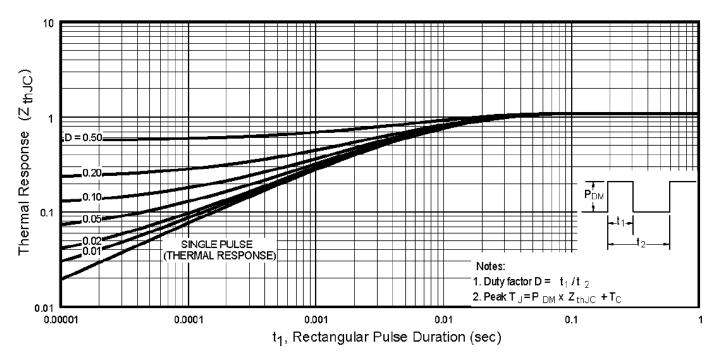


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



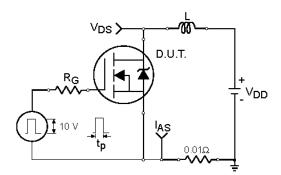


Fig. 12a. Unclamped Inductive Test Circuit

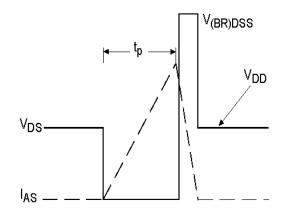


Fig. 12b. Unclamped Inductive Waveforms

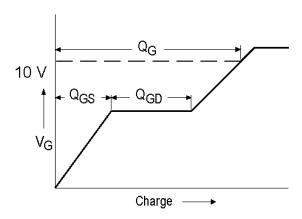
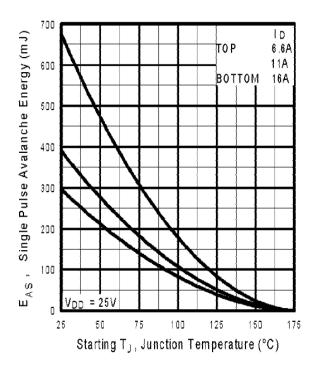


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

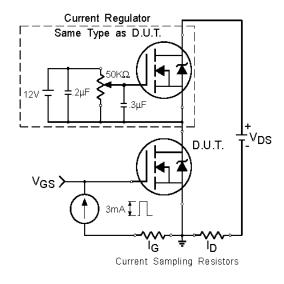
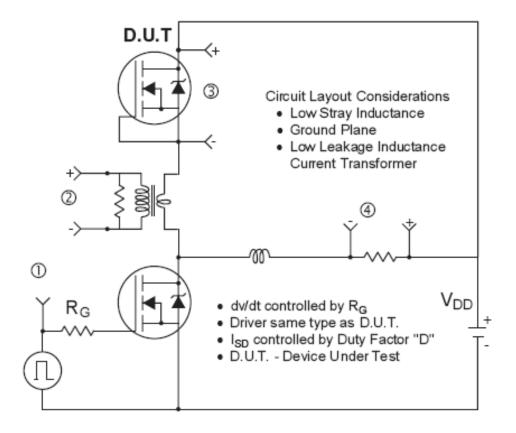


Fig 13b. Gate Charge Test Circuit





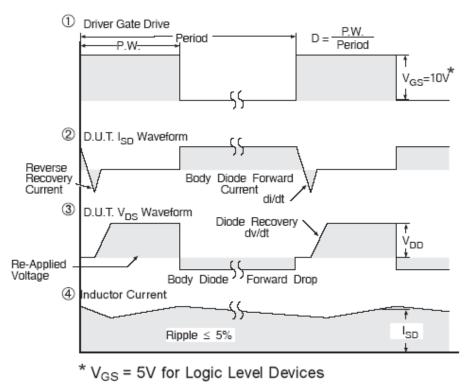
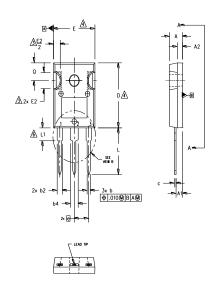
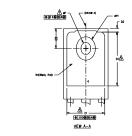


Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

## **(infineon**

#### TO-247AC Package Outline (Dimensions are









#### NOTES:

DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M 1994.

DIMENSIONS ARE SHOWN IN INCHES.

CONTOUR OF SLOT OPTIONAL.

DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS D1 & E1.

LEAD FINISH UNCONTROLLED IN L1.

OP TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5 \* TO THE TOP OF THE PART WITH A MAXIMUM HOLE DIAMETER OF .154 INCH.

OUTLINE CONFORMS TO JEDEC OUTLINE TO-247AC.

	DIMENSIONS				
SYMBOL	INC	HES	MILLIM	ETERS	
	MIN.	MAX.	MIN.	MAX.	NOTES
A	.183	.209	4.65	5.31	
A1	.087	.102	2.21	2.59	
A2	.059	.098	1.50	2.49	
b	.039	.055	0.99	1.40	
ь1	.039	.053	0.99	1.35	
b2	.065	.094	1.65	2.39	
b3	.065	.092	1.65	2.34	
b4	.102	.135	2.59	3.43	
b5	.102	.133	2.59	3.38	
С	.015	.035	0.38	0.89	
c1	.015	.033	0.38	0.84	
D	.776	.815	19.71	20.70	4
D1	.515	-	13.08	-	5
D2	.020	.053	0.51	1.35	
E	.602	.625	15.29	15.87	4
E1	.530	-	13.46	-	
E2	.178	.216	4.52	5.49	
е	.215	BSC	5.46 BSC		
Øk	.0	10	0.	25	
L	.559	.634	14.20	16.10	
L1	.146	.169	3.71	4.29	
ØΡ	.140	.144	3.56	3.66	
øP1	-	.291	-	7.39	
Q	.209	.224	5.31	5.69	
S	.217	BSC	5.51	BSC	
			1		

#### LEAD ASSIGNMENTS

#### <u>HEXFET</u>

- 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4.- DRAIN

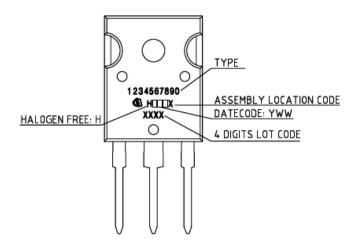
#### IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR 3.- EMITTER
- 4.- COLLECTOR

#### DIODES

- 1.- ANODE/OPEN
- 2.- CATHODE
- 3.- ANODE

#### **TO-247AC Part Marking Information**



TO-247AC package is not recommended for Surface Mount Application.



#### **Revision History**

Date	Rev.	Comments
2024-10-03	2.1	<ul> <li>Update datasheet to Infineon format</li> <li>Updated Part marking –page 8</li> </ul>
		Added disclaimer on last page.

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